

# INTERNATIONAL STANDARD

# IEC 60352-7

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## Solderless connections –

### Part 7: Spring clamp connections – General requirements, test methods and practical guidance

#### *Connexions sans soudure –*

#### *Partie 7: Connexions à ressort – Règles générales, méthodes d'essai et guide pratique*

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International Electrotechnical Commission, 3, rue de Varembé, PO Box 131, CH-1211 Geneva 20, Switzerland  
Telephone: +41 22 919 02 11 Telefax: +41 22 919 03 00 E-mail: [inmail@iec.ch](mailto:inmail@iec.ch) Web: [www.iec.ch](http://www.iec.ch)



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## INTERNATIONAL ELECTROTECHNICAL COMMISSION

### SOLDERLESS CONNECTIONS –

#### Part 7: Spring clamp connections – General requirements, test methods and practical guidance

#### FOREWORD

- 1) The IEC (International Electrotechnical Commission) is a worldwide organization for standardization comprising all national electrotechnical committees (IEC National Committees). The object of the IEC is to promote international co-operation on all questions concerning standardization in the electrical and electronic fields. To this end and in addition to other activities, the IEC publishes International Standards. Their preparation is entrusted to technical committees; any IEC National Committee interested in the subject dealt with may participate in this preparatory work. International, governmental and non-governmental organizations liaising with the IEC also participate in this preparation. The IEC collaborates closely with the International Organization for Standardization (ISO) in accordance with conditions determined by agreement between the two organizations.
- 2) The formal decisions or agreements of the IEC on technical matters express, as nearly as possible, an international consensus of opinion on the relevant subjects since each technical committee has representation from all interested National Committees.
- 3) The documents produced have the form of recommendations for international use and are published in the form of standards, technical specifications, technical reports or guides and they are accepted by the National Committees in that sense.
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- 6) Attention is drawn to the possibility that some of the elements of this International Standard may be the subject of patent rights. The IEC shall not be held responsible for identifying any or all such patent rights.

International Standard IEC 60352-7 has been prepared by subcommittee 48B: Connectors, of IEC technical committee 48: Electromechanical components and mechanical structures for electronic equipment.

The text of this standard is based on the following documents:

FDIS	Report on voting
48B/1228/FDIS	48B/1243/RVD

Full information on the voting for the approval of this standard can be found in the report on voting indicated in the above table.

This publication has been drafted in accordance with the ISO/IEC Directives, Part 3.

The committee has decided that the contents of this publication will remain unchanged until 2007. At this date, the publication will be

- reconfirmed;
- withdrawn;
- replaced by a revised edition, or
- amended.

## INTRODUCTION

This part of IEC 60352 includes requirements, tests and practical guidance information.

Two test schedules are provided.

- a) The basic test schedule applies to spring-clamp connections which conform to all requirements of clause 4. These requirements are derived from experience with successful applications of such spring-clamp connections.
- b) The full test schedule applies to spring-clamp connections which do not fully conform to all requirements of clause 4, for example which are manufactured using materials or finishes not included in clause 4. This approach permits cost and time effective performance verification using a limited basic test schedule for established spring-clamp connections and an expanded full test schedule for spring-clamp connections requiring more extensive performance validation.

The values given in this specification are minimum values, which are harmonized with other IEC documents. Other standards may specify other values.

## SOLDERLESS CONNECTIONS –

### Part 7: Spring clamp connections – General requirements, test methods and practical guidance

#### 1 Scope and object

This part of IEC 60352 is applicable to spring-clamp connections made with stripped wire without further preparation:

- solid conductors of 0,32 mm to 3,7 mm nominal diameter (0,08 mm<sup>2</sup> to 10 mm<sup>2</sup> cross-section), or
- stranded conductors of 0,08 mm<sup>2</sup> to 10 mm<sup>2</sup> cross-section, or
- flexible conductors of 0,08 mm<sup>2</sup> to 10 mm<sup>2</sup> cross-section

according to IEC 60228 or IEC 60189-3 for use in telecommunication equipment and in electronic devices employing similar techniques.

Information on materials and data from industrial experience is included in addition to the test procedures to provide electrically stable connections under prescribed environmental conditions.

The object of this part of IEC 60352 is to determine the suitability of spring-clamp connections under specified mechanical, electrical and atmospheric conditions.

NOTE IEC Guide 109 advocates the need to minimize the impact of a product on the natural environment throughout the product life cycle. It is understood that some of the materials permitted in this standard may have a negative environmental impact. As technological advances lead to acceptable alternatives for these materials, they will be eliminated from this standard.

#### 2 Normative references

The following referenced documents are indispensable for the application of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

IEC 60050(581):1978, *International Electrotechnical Vocabulary (IEV) – Chapter 581: Electro-mechanical components for electronic equipment*  
Amendment 1 (1998)

IEC 60068-1:1988, *Environmental testing – Part 1: General and guidance*  
Amendment 1 (1992)

IEC 60189-3:1988, *Low frequency cables and wires with PVC insulation and PVC sheath – Part 3: Equipment wires with solid or stranded conductor, PVC insulated, in singles, pairs and triples*

IEC 60228:1978, *Conductors of insulated cables*  
Amendment 1 (1993)

IEC 60512 (all parts), *Connectors for electronic equipment – Tests and measurements*

IEC 60512-1-100, *Connectors for electronic equipment – Tests and measurements – Part 1-100: General – Applicable publications*

IEC 60884-1:1994, *Plug and socket-outlets for household and similar purposes – Part 1: General requirements.*